

**Search Notes**

Application/Control No.

10/051,267

Examiner

Thien F. Tran

Applicant(s)/Patent under  
Reexamination

TANAKA ET AL.

Art Unit

2811

**SEARCHED**

Class	Subclass	Date	Examiner
257	59, 66	3/16/2005	TT
257	70, 72	3/16/2005	TT
257	75	3/16/2005	TT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
257	59, 66	3/16/2005	TT
257	70, 72	3/16/2005	TT
257	75	3/16/2005	TT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR